## Search Notes



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Examiner

Loewe, Sun Jae Y

Applicant(s)/Patent Under Reexamination

TAKAHASHI ET AL.

Art Unit

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## **SEARCHED**

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Class	Subclass	Date	Examiner

## **SEARCH NOTES**

Search Notes	Date	Examiner
restriction requirement	1-4-2008	sl

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner
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